



The American Association for Laboratory Accreditation

World Class Accreditation

Accredited Laboratory

A2LA has accredited

SILICON CERT LABORATORIES

Reading, PA


for technical competence in the field of

Mechanical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General Requirements for the Competence of Testing and Calibration Laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009*).

Presented this 21st day of September 2009.





President & CEO
For the Accreditation Council
Certificate Number 2930.01
Valid to November 30, 2011

For the tests or types of tests to which this accreditation applies, please refer to the laboratory's Mechanical Scope of Accreditation.



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

SILICON CERT LABORATORIES
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 Reading, PA 19605
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MECHANICAL

Valid To: November 30, 2011

Certificate Number: 2930.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following tests on Components and Subsystems for Optoelectronics, Telecommunication, Military, Automotive, Aerospace and Medical Devices:

Test Type/Technology	Test Method(s)
Accelerated Bias Age/Burn In/Life	JESD22-A108 MIL-STD-202, Method 108 MIL-STD-750, Methods 1026, 1038, 1039, 1040, 1048 MIL-STD-883, Methods 1005, 1015, 1016, 1030, 1033
High Temp Storage/Stabilization Bake	JESD22-A103, Cond (A thru F and G) AEC-Q100, AEC-Q200 GR-468-CORE (3.3.2.1) MIL-STD-202, Method 108 MIL-STD-750, Method 1031 MIL-STD-883, Method 1008
Low Temperature Storage	JESD22-A119, Cond (A thru C) GR-468-CORE (3.3.2.1)
Temperature Cycle	JESD22-A104 MIL-STD-750, Methods 1051 and 1055 MIL-STD-883, Method 1010 GR-468-CORE
Power Temperature Cycle	JESD22-A105 MIL-STD-883, Method 1007
Thermal Shock	JESD22-A106 MIL-STD-750, Method 1056 MIL-STD-883, Method 1011 MIL-STD-202, Method 107G
Damp Heat (85/85)	GR-468-CORE MIL-STD-202, Method 103B
Highly Accelerated Stress Test (HAST)	JESD22-A118 (unbiased) JESD22-A110 (biased)

Cyclic Moisture	MIL-STD-883, Method 1004 MIL-STD-202, Method 106G MIL-STD-750, Method 1021 MIL-STD-810, Method 507 JESD22-A100 GR-1221-CORE
Autoclave	JESD22-A102
Temperature Humidity Bias (THB)	JESD22-A101B MIL-STD-202, Method 103
Preconditioning	JESD22-A113 AEC-Q100, AEC-Q101
Moisture Sensitivity Level (MSL)	J-STD-020 J-STD-035 CSAM
Solderability	JESD22-B102, Methods 1 and 2 JSTD-002 AEC-Q100, AEC-Q101, AEC-Q200 MIL-STD-883, Method 2003 MIL-STD-750, Method 2026
Mechanical Shock	JESD22-B104 AEC-Q100, AEC-Q101, AEC-Q200 GR-468-CORE MIL-STD-883, Method 2002 MIL-STD-750, Method 2016 MIL-STD-202, Method 213 Cond (A thru F and J)
Variable Frequency Vibration	JESD22-B103 AEC-Q100, AEC-Q101 MIL-STD-883, Methods 2007 MIL-STD-750, Methods 2056 MIL-STD-202 Method 201A
Random Vibration	MIL-STD-883, Method 2026, Cond 1 (A thru K), Cond 2 (A thru J) MIL-STD-202, Method 214, Cond 1 (A thru J), Cond 2 (A thru J)
Fiber Integrity	GR-468-CORE (3.3.1.3.1 and 3.3.1.3.2) GR-326-CORE (3.3.1.3.3)
Fine Leak (He) Seal	MIL-STD-883, Method 1014, A1, A2 MIL-STD-750, Method 1071H MIL-STD-202, Method 112 JESD22-A109
Gross Leak (NID) Seal	MIL-STD-883, Method 1014, C3 MIL-STD-750, Method 1071K MIL-STD-202, Method 112 JESD22-A109
Constant Acceleration	MIL-STD-883, Method 2001 MIL-STD-202, Method 212A MIL-STD-750; Method 2006 AEC-Q100, AEC-Q101
Resistance to Solvents	JESD22-B107 AEC-Q101, AEC-Q200 MIL-STD-750, Method 1022 MIL-STD-883, Method 2015 MIL-STD-202, Method 215K



Gate Leakage	AEC Q100-006
ESD-HBM	JESD22-A114 MIL-STD-883, Method 3015 GR-468-CORE TR-NWT-000870 TIA/EIA FOTP-129 AEC-Q100-002, AEC-Q200-002, AEC-Q101-001 ESD STM5.1-2001
ESD-MM	JESD22-A115 AEC-Q100-003, AEC-Q101-002
High Temperature Operating Life (HTOL)	JESD22-A108 AEC-Q100
Resistance to Solder Heat	MIL-STD 883, Method 2036, Cond A, B, I, J and K MIL-STD-750, Method 2031 MIL-STD-202, Method 210F, Cond A, B, I, J and K AEC-Q101, AEC-Q200 JESD22-B106
Vibration Fatigue	MIL-STD-750, Method 2046
High Temp Reverse Bias (HTRB)	AEC-Q101 JESD22-A108 MIL-STD-750, Method 1042 MIL-STD-883, Method 1005
High Temp Gate Bias (HTGB)	AEC-Q101 JESD22-A108 MIL-STD-750, Method 1042 MIL-STD-883, Method 1005
Cycled THB	JESD22-A100C MIL-STD-883, Method 1004 MIL-STD-750, Method 1021
Early Life Failure Rate (ELFR)	AEC-Q100-008
External Visual	JESD22-B101A MIL-STD-883, Method 2009 MIL-STD-750, Method 2071
Intermittent Life	MIL-STD-883, Method 1006, 1005 MIL-STD-750, Method 1036